

U.S. Patent Application Serial No. 10/648,483
Amendment filed June 6, 2005
Reply to OA dated May 17, 2005

AMENDMENTS TO THE CLAIMS:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1 Claim 1 (currently amended): A measuring device for measuring an in-plane magnetization
2 vector component of a magnetic substance to be measured, comprising:
3 a light source;
4 a focusing unit for focusing light flux from said light source and irradiating it to the magnetic
5 substance to be measured;
6 a polarization split detector for detecting a light amount of a polarization component in one
7 direction or separated for separating each component of polarization components orthogonal to each
8 other using a polarizer and photo-detectors in order to detect a change in polarization state or light
9 amount of the light flux reflected by the magnetic substance to be measured due to a magneto-optical
10 effect; and
11 a half-turn asymmetric polarizing element acting only on the reflected light from the
12 magnetic substance to be measured and acting in such a manner that its action on polarization
13 distribution in a cross section of incident light flux has asymmetry an asymmetric nature of about
14 a half-turn around an optical axis.

U.S. Patent Application Serial No. 10/648,483
Amendment filed June 6, 2005
Reply to OA dated May 17, 2005

1 Claim 2 (currently amended): The measuring device according to claim 1,
2 wherein said half-turn asymmetric polarizing element is a half-turn asymmetric reflectional
3 symmetry polarizing element whose action on the incident light flux has reflectional symmetry
4 nature with respect to a certain plane including the optical axis so that only one component of the
5 in-plane magnetization vectors of the magnetic substance to be measured can be measured separately
6 from the other [[two]] orthogonal components.

1 Claim 3 (original): The measuring device according to claim 1,
2 wherein said half-turn asymmetric polarizing element is a divisional half-wave element
3 constituted of a half-wave element acting on a part of the cross section of the light flux to generate
4 half-wave phase difference, or half-wave elements having different neutral axis azimuths in divided
5 regions in the cross section of the light flux.

1 Claim 4 (currently amended): The measuring device according to claim 1,
2 wherein said half-turn asymmetric polarizing element is a divisional polarization rotation
3 element having ~~ununiform~~ non-uniform polarization rotation action in the cross section of the light
4 flux.

1 Claim 5 (currently amended): The measuring device according to claim 1,
2 wherein said half-turn asymmetric polarizing element is a divisional phase modulator capable

U.S. Patent Application Serial No. 10/648,483
Amendment filed June 6, 2005
Reply to OA dated May 17, 2005

3 of controlling a phase difference generated in each divisional region from outside.

1 Claim 6 (original): The measuring device according to claim 1,
2 wherein the photo-detector has an image detection element and an imaging lens for forming
3 an image on the image detection element so that image data of in-plane magnetized distribution of
4 the magnetic substance to be measured can be obtained.

1 Claim 7 (original): The measuring device according to claim 1,
2 wherein said focusing unit includes a near-field probe for generating near-field light and a
3 focusing part for focusing propagation light generated as a result of interaction of the near-field light
4 and the magnetic substance to be measured.

1 Claim 8 (currently amended): The measuring device according to claim 1, further
2 comprising:
3 a probe having [[a]] the magnetic substance,
4 wherein the magnetization vector components component of the magnetic substance of said
5 probe are measured so that spatial magnetic field vector components at a probe position can be
6 measured.

U.S. Patent Application Serial No. 10/648,483
Amendment filed June 6, 2005
Reply to OA dated May 17, 2005

1 Claim 9 (original): The measuring device according to claim 1, further comprising:
2 a light scanning unit for scanning a focusing spot position where a light beam from said light
3 source is focused by said focusing unit; and
4 an automatic position control stage for moving and controlling a position of said half-turn
5 asymmetric polarizing element in synchronization with scanning in at least one direction by said
6 light scanning unit.

1 Claim 10 (original): The measuring device according to claim 1, further comprising:
2 a relay lens for optically aligning a position of the light flux incident on said half-turn
3 asymmetric polarizing element with a position of a pupil of said focusing unit.

1 Claim 11 (original): The measuring device according to claim 1,
2 wherein said half-turn asymmetric polarizing element receives passed light or passed and
3 reciprocated light through the magnetic substance to be measured, and measures polarization rotation
4 of the magnetic substance to be measured due to a Faraday effect.

1 Claim 12 (original): The measuring device according to claim 1,
2 wherein said focusing unit includes a solid immersion lens.

U.S. Patent Application Serial No. 10/648,483
Amendment filed June 6, 2005
Reply to OA dated May 17, 2005

1 Claim 13 (currently amended): The measuring device according to claim 1, further
2 comprising:

3 a probe having [[a]] the magnetic substance in a focusing part of said focusing unit,
4 wherein the magnetization vector components component of the magnetic substance of said
5 probe are measured so that spatial magnetic field vector components at a position where said probe
6 is placed can be measured.

1 Claim 14 (currently amended): The measuring device according to claim 1,
2 wherein said focusing unit is constituted of a focusing lens or a focusing mirror, [[and]] a
3 light scattering type near-field probe arranged at a focusing position thereof and having a sharp tip,
4 [[and]] wherein the light scattered at the probe tip and the magnetic substance to be measured is
5 focused to detect change in polarization state or reflectivity thereof.

1 Claim 15 (original): The measuring device according to claim 2,
2 wherein said half-turn asymmetric reflectional symmetry polarizing element is divided by
3 a straight line in two regions in the cross section of light flux, and each of the two regions is
4 constituted of a half-wave element whose angles of a neutral axis from the straight line are +22.5
5 degree and -22.5 degree.

U.S. Patent Application Serial No. 10/648,483
Amendment filed June 6, 2005
Reply to OA dated May 17, 2005

1 Claim 16 (currently amended): The measuring device according to claim 1, further
2 comprising:

3 a Faraday cell provided before or after the magnetic substance to be measured or in an optical
4 path where the light reflected by the magnetic substance to be measured reciprocates,
5 wherein a position and modulation spatial distribution of said half-turn asymmetric
6 polarizing element are controlled to minimize a modulation amount of an output signal of said
7 polarization split detector caused by modulation of said Faraday cell so that a position where
8 detectivity detection of to a perpendicular magnetization vector component is minimized can be
9 found.

1 Claim 17 (currently amended): The measuring device according to claim 1, further
2 comprising:

3 a Faraday cell which is provided before or after the magnetic substance to be measured or
4 in an optical path where the light reflected by the magnetic substance to be measured reciprocates
5 and whose polarization rotation angle is previously corrected; and
6 a conversion unit for registering a relationship between an output of said polarization split
7 detector and a polarization rotation angle by said Faraday cell in a state of measuring a
8 perpendicular magnetization vector component, and converting the output of said polarization split
9 detector to the polarization rotation angle using the registered relationship in measuring the in-plane
10 magnetization vector component.

U.S. Patent Application Serial No. 10/648,483

Amendment filed June 6, 2005

Reply to OA dated May 17, 2005

1 Claim 18 (currently amended): A measuring device comprising:

2 a half-turn asymmetric reflectional symmetry polarized light source, as a light source, for
3 outputting light flux whose intensity distribution has ~~symmetry~~ a symmetric nature while
4 polarization state distribution does not have ~~symmetry~~ an asymmetric nature of about a half-turn
5 around an optical axis in a cross section of the light flux perpendicular to the optical axis, as well
6 as whose intensity distribution and polarization state distribution in the cross section of the light
7 flux are both symmetric about a reflection with respect to a certain plane including the optical axis
8 as a boundary plane;

9 a focusing unit for focusing the light flux from said half-turn asymmetric reflectional
10 symmetry polarized light source and irradiating it to a magnetic substance to be measured; and

11 a polarization split detector for detecting a light amount of a polarization component in one
12 direction or ~~separated~~ for separating each component of polarization components orthogonal to each
13 other using a polarizer and photo-detectors in order to detect a change in polarization state or light
14 amount of the light flux reflected by the magnetic substance to be measured due to a magneto-
15 optical effect,

16 wherein an optical element, existing in an optical path from the light output of said light
17 source to a position immediately before said polarization split detector and acting on the light flux,
18 has action acts on light intensity distribution and polarization distribution in the light flux which
19 is symmetric around half-turn around an optical axis and reflection with respect to the boundary

U.S. Patent Application Serial No. 10/648,483
Amendment filed June 6, 2005
Reply to OA dated May 17, 2005

20 plane, and one or two polarization split detection azimuths orthogonal to each other of said
21 polarization split detector and the boundary plane or a reflectional symmetry plane of the light flux
22 incident, when there is no magneto-optical action by the magnetic substance to be measured, is set
23 to make angles of integral multiples of 90 degrees, so that only one component of in-plane
24 magnetization vectors of the magnetic substance to be measured can be measured separately from
25 the other [[two]] orthogonal components.

1 Claim 19 (currently amended): The measuring device according to claim 18,
2 wherein said half-turn asymmetric reflectional symmetry polarized light source includes:
3 a natural light source, a partially polarized light source, or a linearly polarized light source;
4 and

5 a divisional polarizer constituted of a polarizer which takes one of the polarization
6 components and ~~ununiformly acting acts non-uniformly~~ in a cross section of light flux outputted
7 from the linearly polarized light source.

1 Claim 20 (currently amended): The measuring device according to claim 18,
2 wherein said half-turn asymmetric reflectional symmetry polarized light source includes:
3 a linearly polarized light source; and
4 a divisional half-wave element having an element which generates a half-wave phase
5 difference and ~~ununiformly acting acts non-uniformly~~ in a cross section of light flux outputted from

U.S. Patent Application Serial No. 10/648,483
Amendment filed June 6, 2005
Reply to OA dated May 17, 2005

6 the linearly polarized light source.

1 Claim 21 (currently amended): The measuring device according to claim 18,
2 wherein said half-turn asymmetric reflectional symmetry polarized light source includes:
3 a linearly polarized light source; and
4 a divisional polarization rotation element having an element which rotates the polarization
5 and uniformly acting acts non-uniformly in a cross section of light flux outputted from the linear
6 polarized light source.

1 Claim 22 (currently amended): A measuring device for separately measuring only one
2 component of in-plane magnetization vectors of a magnetic substance to be measured separately
3 from the other [[two]] orthogonal components, comprising:
4 a light source;
5 a focusing unit for focusing light flux from said light source and irradiating it to the
6 magnetic substance to be measured;
7 a polarization split detector for detecting a light amount of a polarization component in one
8 direction or separated for separating each component of polarization components orthogonal to each
9 other using a polarizer and photo-detectors to detect change in polarization state or light amount of
10 the light flux reflected by the magnetic substance to be measured due to a magneto-optical effect;
11 and

U.S. Patent Application Serial No. 10/648,483
Amendment filed June 6, 2005
Reply to OA dated May 17, 2005

12 a divisional half-wave element placed in an optical path between said light source and said
13 focusing unit where the light reciprocates, and constituted of half-wave elements which are divided
14 into two regions with a straight line as a boundary in a cross section of the light flux and whose
15 respective neutral axes in the two regions and the boundary make angles of the same absolute value
16 with opposite signs.

1 Claim 23 (currently amended): A measuring device for measuring an in-plane
2 magnetization vector component of a magnetic substance to be measured, comprising:
3 a light source;
4 a focusing unit for focusing light flux from said light source and irradiating it to the
5 magnetic substance to be measured;
6 a polarization split detector for detecting a light amount of a polarization component in one
7 direction or separated for separating each component of polarization components orthogonal to each
8 other using a photo-detector to detect a change in polarization state or light amount of the light flux
9 reflected by the magnetic substance to be measured due to a magneto-optical effect; and
10 a divisional half-wave element in an optical path before said focusing unit where the light
11 reciprocates, whose action on the polarization distribution in a cross section of the light flux has
asymmetry an asymmetric nature of about a half-turn around an optical axis.

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